

## 1/16, 1/32 DUTY LCD CONTROLLER/DRIVER WITH RAM

**DESCRIPTION**

$\mu$ PD16676 is a controller/driver containing RAMs capable of full-dot LCD displays. One of these IC chips can drive the full-dot LCD up to 61-by-16 dots.

These ICs are the most suitable for Kanji character or Chinese character pagers, as well as graphic pagers, displaying 16-by-16 dots per character.

**FEATURES**

- LCD driver with built-in display RAM
- Dot display RAM: 2560 bits
- Output: 61 segments & 16 commons
- 8-bit parallel interface
- Oscillation circuit incorporated

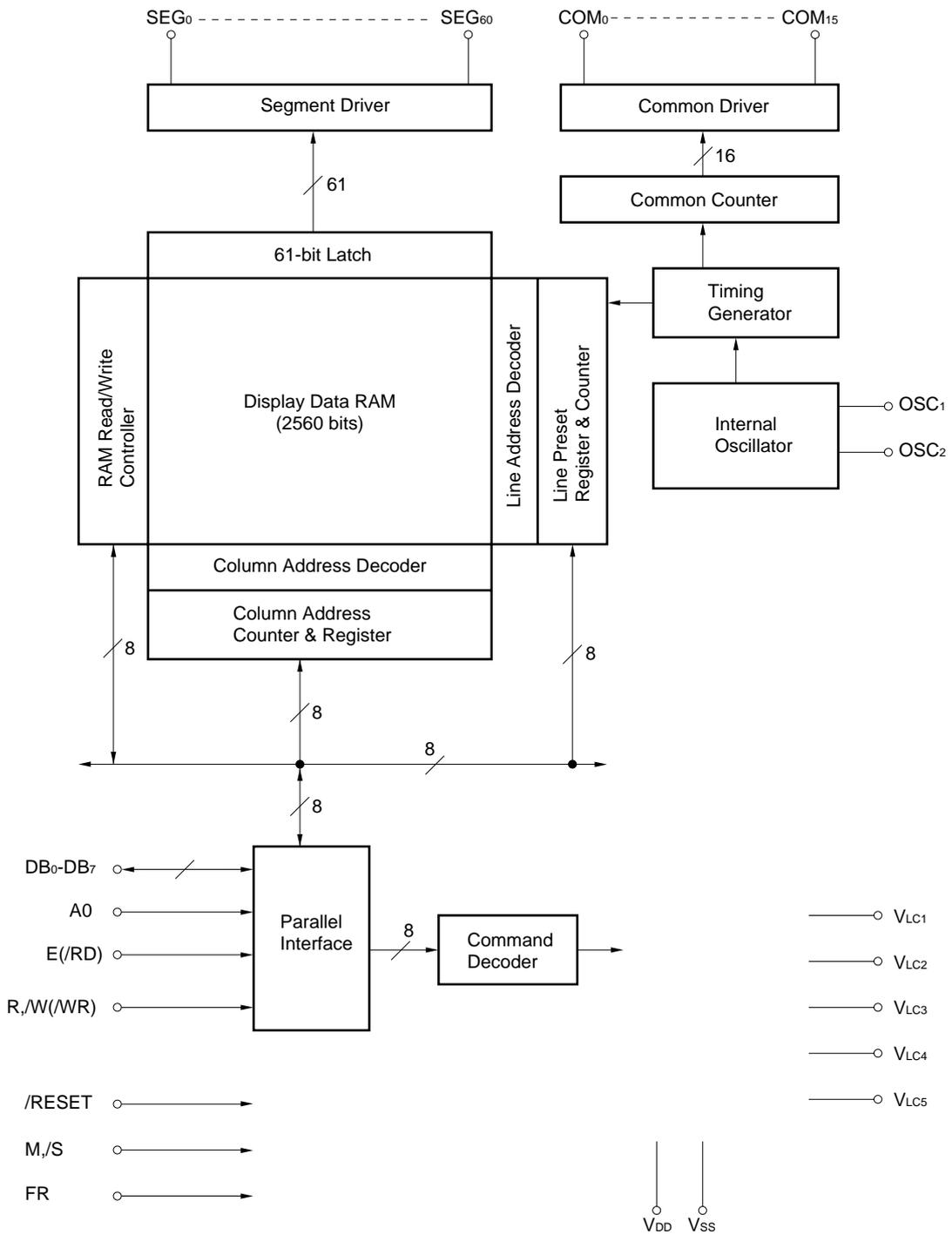
**★ ORDERING INFORMATION**

Part Number	Package
$\mu$ PD16676P	Chips
$\mu$ PD16676W	Wafer

**Remark** Purchasing the above products in terms of chips per wafer requires an exchange of other documents as well, including a memorandum of the product quality. Therefore, those who are interested in this regard are advised to contact one of our sales representatives for further details.

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Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

★ 1. BLOCK DIAGRAM



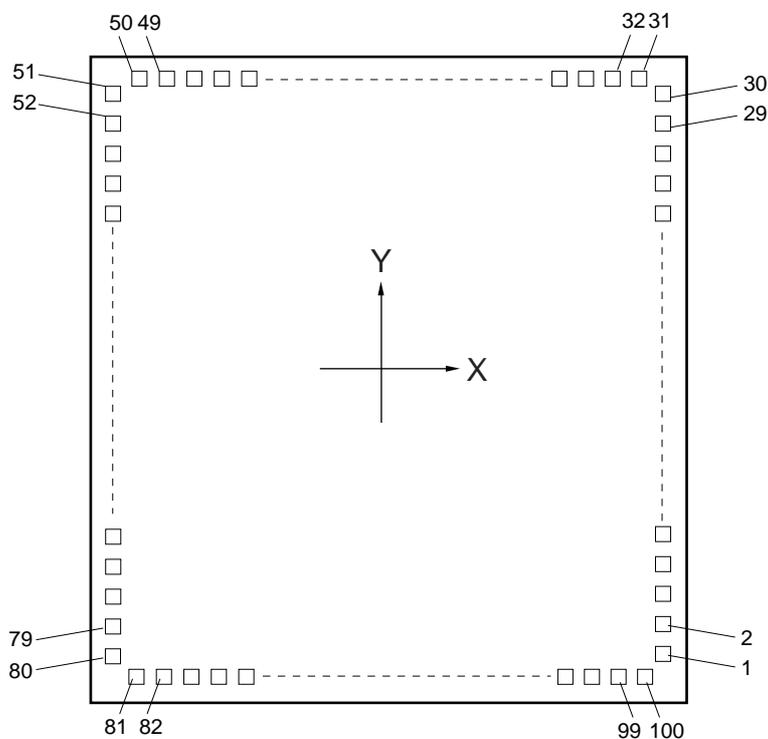
**Remark** /xxx indicates active low signals.

★ 2. PIN CONFIGURATION (PAD LAYOUT)

Chip Size : 4.04 x 5.53 mm<sup>2</sup>

Pad Size Al Area : 120 x 120  $\mu$ m<sup>2</sup>

Pad Size Open Area : 108 x 108  $\mu$ m<sup>2</sup>



**Table2-1. Pad Connection**

Pin No.	Pin Symbol	I/O
1	COM <sub>5</sub>	Output
2	COM <sub>6</sub>	Output
3	COM <sub>7</sub>	Output
4	COM <sub>8</sub>	Output
5	COM <sub>9</sub>	Output
6	COM <sub>10</sub>	Output
7	COM <sub>11</sub>	Output
8	COM <sub>12</sub>	Output
9	COM <sub>13</sub>	Output
10	COM <sub>14</sub>	Output
11	COM <sub>15</sub>	Output
12	SEG <sub>60</sub>	Output
13	SEG <sub>59</sub>	Output
14	SEG <sub>58</sub>	Output
15	SEG <sub>57</sub>	Output
16	SEG <sub>56</sub>	Output
17	SEG <sub>55</sub>	Output
18	SEG <sub>54</sub>	Output
19	SEG <sub>53</sub>	Output
20	SEG <sub>52</sub>	Output
21	SEG <sub>51</sub>	Output
22	SEG <sub>50</sub>	Output
23	SEG <sub>49</sub>	Output
24	SEG <sub>48</sub>	Output
25	SEG <sub>47</sub>	Output
26	SEG <sub>46</sub>	Output
27	SEG <sub>45</sub>	Output
28	SEG <sub>44</sub>	Output
29	SEG <sub>43</sub>	Output
30	SEG <sub>42</sub>	Output
31	SEG <sub>41</sub>	Output
32	SEG <sub>40</sub>	Output
33	SEG <sub>39</sub>	Output
34	SEG <sub>38</sub>	Output
35	SEG <sub>37</sub>	Output
36	SEG <sub>36</sub>	Output
37	SEG <sub>35</sub>	Output
38	SEG <sub>34</sub>	Output
39	SEG <sub>33</sub>	Output
40	SEG <sub>32</sub>	Output
41	SEG <sub>31</sub>	Output
42	SEG <sub>30</sub>	Output
43	SEG <sub>29</sub>	Output
44	SEG <sub>28</sub>	Output
45	SEG <sub>27</sub>	Output
46	SEG <sub>26</sub>	Output
47	SEG <sub>25</sub>	Output
48	SEG <sub>24</sub>	Output
49	SEG <sub>23</sub>	Output
50	SEG <sub>22</sub>	Output

Pin No.	Pin Symbol	I/O
51	SEG <sub>21</sub>	Output
52	SEG <sub>20</sub>	Output
53	SEG <sub>19</sub>	Output
54	SEG <sub>18</sub>	Output
55	SEG <sub>17</sub>	Output
56	SEG <sub>16</sub>	Output
57	SEG <sub>15</sub>	Output
58	SEG <sub>14</sub>	Output
59	SEG <sub>13</sub>	Output
60	SEG <sub>12</sub>	Output
61	SEG <sub>11</sub>	Output
62	SEG <sub>10</sub>	Output
63	SEG <sub>9</sub>	Output
64	SEG <sub>8</sub>	Output
65	SEG <sub>7</sub>	Output
66	SEG <sub>6</sub>	Output
67	SEG <sub>5</sub>	Output
68	SEG <sub>4</sub>	Output
69	SEG <sub>3</sub>	Output
70	SEG <sub>2</sub>	Output
71	SEG <sub>1</sub>	Output
72	SEG <sub>0</sub>	Output
73	A0	Input
74	OSC <sub>1</sub>	Input
75	OSC <sub>2</sub>	Output
76	E(/RD)	Input
77	R,/W(/WR)	Input
78	V <sub>SS</sub>	—
79	DB <sub>0</sub>	Input/Output
80	DB <sub>1</sub>	Input/Output
81	DB <sub>2</sub>	Input/Output
82	DB <sub>3</sub>	Input/Output
83	DB <sub>4</sub>	Input/Output
84	DB <sub>5</sub>	Input/Output
85	DB <sub>6</sub>	Input/Output
86	DB <sub>7</sub>	Input/Output
87	V <sub>DD</sub>	—
88	/RESET	Input
89	FR	Input/Output
90	V <sub>LC5</sub>	—
91	V <sub>LC3</sub>	—
92	V <sub>LC2</sub>	—
93	M,/S	Input
94	V <sub>LC4</sub>	—
95	V <sub>LC1</sub>	—
96	COM <sub>0</sub>	Output
97	COM <sub>1</sub>	Output
98	COM <sub>2</sub>	Output
99	COM <sub>3</sub>	Output
100	COM <sub>4</sub>	Output

Table2-2. Pad Layout

Pin No.	X (μm)	Y (μm)	Pin No.	X (μm)	Y (μm)	Pin No.	X (μm)	Y (μm)
1	1771	-2230	36	668.8	2517.2	71	-1771	-757.2
2	1771	-2076	37	518.8	2517.2	72	-1771	-907.2
3	1771	-1922	38	368.8	2517.2	73	-1767.8	-1149.4
4	1771	-1768	39	218.8	2517.2	74	-1767.8	-1299.4
5	1771	-1614	40	68.8	2517.2	75	-1767.8	-1489.4
6	1771	-1460	41	-81.2	2517.2	76	-1767.8	-1639.4
7	1771	-1306	42	-231.2	2517.2	77	-1767.8	-1839.4
8	1771	-1152	43	-381.2	2517.2	78	-1767.8	-1989.4
9	1771	-998	44	-531.2	2517.2	79	-1767.8	-2139.4
10	1771	-844	45	-681.2	2517.2	80	-1767.8	-2289.4
11	1771	-690	46	-831.2	2517.2	81	-1745	-2513.4
12	1771	-536	47	-981.2	2517.2	82	-1595	-2513.4
13	1771	-382	48	-1131.2	2517.2	83	-1395	-2513.4
14	1771	-228	49	-1281.2	2517.2	84	-1245	-2513.4
15	1771	-74	50	-1431.2	2517.2	85	-1045	-2513.4
16	1771	80	51	-1771	2242.8	86	-895	-2513.4
17	1771	234	52	-1771	2092.8	87	-682.6	-2513.4
18	1771	388	53	-1771	1942.8	88	-532.2	-2513.4
19	1771	542	54	-1771	1792.8	89	-382.2	-2513.4
20	1771	696	55	-1771	1642.8	90	-106.6	-2513.4
21	1771	850	56	-1771	1492.8	91	69.8	-2513.4
22	1771	1004	57	-1771	1342.8	92	219.8	-2513.4
23	1771	1158	58	-1771	1192.8	93	369.8	-2513.4
24	1771	1312	59	-1771	1042.8	94	569.8	-2513.4
25	1771	1466	60	-1771	892.8	95	719.8	-2513.4
26	1771	1620	61	-1771	742.8	96	952.4	-2513.4
27	1771	1774	62	-1771	592.8	97	1102.4	-2513.4
28	1771	1928	63	-1771	442.8	98	1252.4	-2513.4
29	1771	2082	64	-1771	292.8	99	1402.4	-2513.4
30	1771	2236	65	-1771	142.8	100	1552.4	-2513.4
31	1418.8	2517.2	66	-1771	-7.2			
32	1268.8	2517.2	67	-1771	-157.2			
33	1118.8	2517.2	68	-1771	-307.2			
34	968.8	2517.2	69	-1771	-457.2			
35	818.8	2517.2	70	-1771	-607.2			

**5. PIN FUNCTIONS**

**5.1 Power System**

Pin Symbol	Pin Name	Pin No.	I/O	Description
V <sub>DD</sub>	Power supply pin	87	—	Power supply
V <sub>SS</sub>	Ground	78	—	Ground
V <sub>LC1</sub> to V <sub>LC5</sub>	Reference power supply for drivers	90,91,92,94,95	—	Reference power supply for LCD driving

**5.2 Logic system**

Pin Symbol	Pin Name	Pin No.	I/O	Description
M,/S	Master/Slave selection	93	Input	Switches between the master chip and the slave chip.
FR	LCD to AC signal	89	Input/ Output	Exchanges synchronizing signals (LCD-to-AC signals) in connecting cascades. This pin is for output if the chip is the master, and for input if the chip is the slave.
DB <sub>0</sub> to DB <sub>7</sub>	Data Bus	79 to 86	Input/ Output	Data inputs/outputs
A0	Data/Instruction Switching	73	Input	This pin is used for switching between the display data and the instruction. High level : Display data Low level : Instruction
/RESET	Reset and 68/80-series switching	88	Input	This pin performs reset at the edge of the low-level pulse. At that level, it performs switching 68/80 series modes. High level : 68 series CPU interface Low level : 80 series CPU interface
E(/RD)	Enable and read enable	76	Input	68 series mode : Enable signal 80 series mode : Read enable signal
R,/W(/WR)	Read/Write and Write enable	77	Input	68 series mode : Read/Write signal 80 series mode : Write enable signal
OSC <sub>1</sub>	Oscillation pin	74	Input	Oscillation (connected with a register between OSC <sub>2</sub> )
OSC <sub>2</sub>	Oscillation pin	75	Output	Oscillation (connected with a register between OSC <sub>1</sub> )

**5.3 Driver System**

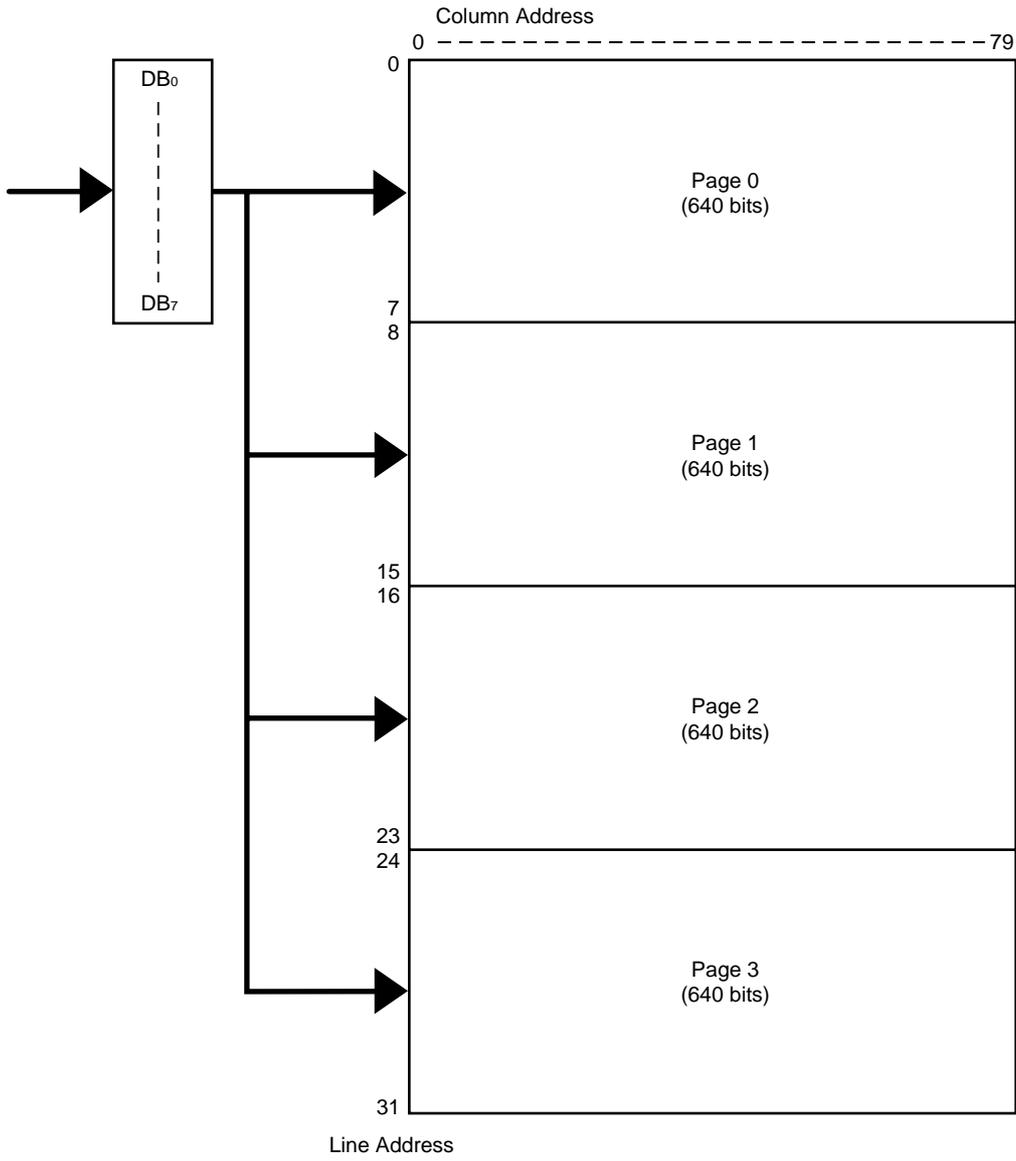
Pin Symbol	Pin Name	Pin No.	I/O	Description
SEG <sub>0</sub> to SEG <sub>60</sub>	Segment	72 to 12	Output	Segment output pins
COM <sub>0</sub> to COM <sub>15</sub>	Common	96 to 100, 1 to 11	Output	Common output pins If the chip is a slave, these pins correspond to COM <sub>16</sub> to COM <sub>31</sub> .

4. COMMANDS

Command	/RD	/WR	A0	DB <sub>7</sub>	DB <sub>6</sub>	DB <sub>5</sub>	DB <sub>4</sub>	DB <sub>3</sub>	DB <sub>2</sub>	DB <sub>1</sub>	DB <sub>0</sub>	Function	
1 Display ON/OFF	1	0	0	1	0	1	0	1	1	1	0/1	ON/OFF of the whole display is performed independent of the display RAM's data or internal state. 1: ON, 0: OFF (Power save at static drive ON) <sup>Note</sup>	
2 Display start line	1	0	0	1	1	0	Display start address (0 to 31)				Determines the RAM line displayed on the uppermost line (COM <sub>0</sub> ) of the display.		
3 Page address set	1	0	0	1	0	1	1	1	0	Pages (0 to 3)		Sets display RAM pages in the page address register.	
4 Column(segment) address set	1	0	0	0	Column addresses (0 to 79)							Sets display RAM's column address in the column address register.	
5 Status read	0	1	0	B U S Y	A D C	O N / O F F	R E S E T	0	0	0	0	Reads status BUSY 1: During internal operation 0: READY status ADC 1: Clockwise output(Normal rotation) 0: Counterclockwise output (Reverse) ON/OFF 1: Display OFF, 0: Display ON RESET 1: Being reset, 0: Normal	
6 Display data write	1	0	1	Write Data								Displays the data bus data and writes it onto the display RAM.	Accesses the display RAM of a pre-specified address. After access, the column address is incremented.
7 Display data read	0	1	1	Read data								Reads the data in the display RAM onto the data bus.	
8 ADC select	1	0	0	1	0	1	0	0	0	0	0/1	This command is used to reverse the correspondence relationship between display RAM's column addresses and segment driver outputs. 0: Clockwise output (Normal rotation) 1: Counterclockwise output (Reverse)	
9 Static drive ON/OFF	1	0	0	1	0	1	0	0	1	0	0/1	Selects between the normal display operation and the static all-lamp-driven display. 1: Static drive (Power save) <sup>Note</sup> 0: Normal display operation	
10 Duty select	1	0	0	1	0	1	0	1	0	0	0/1	Selects between two different liquid-crystal cell driving duties. 1: 1/32 duty 0: 1/16 duty	
11 Read modify write	1	0	0	1	1	1	0	0	0	0	0	Increments the column address counter only when writing the display data; but not when reading it.	
12 END	1	0	0	1	1	1	0	1	1	1	0	Cancels read modify write mode	
13 Reset	1	0	0	1	1	1	0	0	0	1	0	Sets the display start line register to the first line. Sets the column address counter and the page address register to 0.	

**Note** If the static drive is turned ON in the display OFF state, the machine is placed in the power save state.

5. DISPLAY RAM MAP





**7. ELECTRICAL SPECIFICATIONS**

**Absolute Maximum Ratings (T<sub>A</sub> = 25°C, V<sub>SS</sub> = 0 V)**

Parameter	Symbol	Rating	Unit
Supply voltage	V <sub>DD</sub>	-0.3 to +6.5	V
Driver reference supply input voltage	V <sub>LC1</sub> to V <sub>LC4</sub>	V <sub>DD</sub> - 13 to V <sub>DD</sub> + 0.3	V
	V <sub>LC5</sub>	V <sub>DD</sub> - 13 to +0.3	V
Logic system input voltage	V <sub>IN1</sub>	-0.3 to V <sub>DD</sub> + 0.3	V
Logic system output voltage	V <sub>OUT1</sub>	-0.3 to V <sub>DD</sub> + 0.3	V
Logic system input/output voltage	V <sub>I/O1</sub>	-0.3 to V <sub>DD</sub> + 0.3	V
Driver system output voltage	V <sub>OUT2</sub>	V <sub>LC5</sub> - 0.3 to V <sub>DD</sub> + 0.3	V
Operating ambient temperature	T <sub>A</sub>	-40 to +85	°C
Storage temperature	T <sub>stg</sub>	-65 to +150	°C

**Cautions**1. Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

2. Ensure that the phase relationship is V<sub>DD</sub> ≥ V<sub>LC1</sub> ≥ V<sub>LC2</sub> ≥ V<sub>LC3</sub> ≥ V<sub>LC4</sub> ≥ V<sub>LC5</sub>.

★ **Recommended Operating Range (T<sub>A</sub> = -40 to +85°C, V<sub>SS</sub> = 0 V)**

Parameter	Symbol	MIN.	TYP.	MAX.	Unit
Supply voltage	V <sub>DD</sub>	2.7		5.5	V
Reference supply voltage	V <sub>LC1</sub> to V <sub>LC4</sub>	V <sub>DD</sub> - 12		V <sub>DD</sub>	V
	V <sub>LC5</sub>	V <sub>DD</sub> - 12		0	V
Logic system input voltage	V <sub>IN1</sub>	0		V <sub>DD</sub>	V

**Electrical Characteristics (Unless otherwise specified, T<sub>A</sub> = -40 to +85°C, V<sub>DD</sub> = 2.7 to 5.5 V)**

Parameter	Symbol	Condition	MIN.	TYP. <sup>Note</sup>	MAX.	Unit
High-level input voltage	V <sub>IH1</sub>	A0, DB <sub>0</sub> to DB <sub>7</sub> , E, R, <sub>1</sub> /W	0.8 V <sub>DD</sub>			V
	V <sub>IH2</sub>	FR, M, <sub>1</sub> /S, /RESET	0.8 V <sub>DD</sub>			V
Low-level input voltage	V <sub>IL1</sub>	A0, DB <sub>0</sub> to DB <sub>7</sub> , E, R, <sub>1</sub> /W			0.2 V <sub>DD</sub>	V
	V <sub>IL2</sub>	FR, M, <sub>1</sub> /S, /RESET			0.2 V <sub>DD</sub>	V
High-level input current	I <sub>IH</sub>	A0, E, R, <sub>1</sub> /W, /RESET			1	μA
Low-level input current	I <sub>IL</sub>	A0, E, R, <sub>1</sub> /W, /RESET			-1	μA
High-level output voltage	V <sub>OH1</sub>	I <sub>OUT</sub> = -3 mA, DB <sub>0</sub> to DB <sub>7</sub> , V <sub>DD</sub> = 4.5 to 5.5 V	0.8 V <sub>DD</sub>			V
	V <sub>OH2</sub>	I <sub>OUT</sub> = -2 mA, FR, V <sub>DD</sub> = 4.5 to 5.5 V	0.8 V <sub>DD</sub>			V
	V <sub>OH3</sub>	I <sub>OUT</sub> = -120 μA, OSC <sub>2</sub> , V <sub>DD</sub> = 4.5 to 5.5 V	0.8 V <sub>DD</sub>			V
Low-level output voltage	V <sub>OL1</sub>	I <sub>OUT</sub> = 3 mA, DB <sub>0</sub> to DB <sub>7</sub> , V <sub>DD</sub> = 4.5 to 5.5 V			0.2 V <sub>DD</sub>	V
	V <sub>OL2</sub>	I <sub>OUT</sub> = 2 mA, FR, V <sub>DD</sub> = 4.5 to 5.5 V			0.2 V <sub>DD</sub>	V
	V <sub>OL3</sub>	I <sub>OUT</sub> = 120 μA, OSC <sub>2</sub> , V <sub>DD</sub> = 4.5 to 5.5 V			0.2 V <sub>DD</sub>	V
High-level output voltage	V <sub>OH1</sub>	I <sub>OUT</sub> = -1.5 mA, DB <sub>0</sub> to DB <sub>7</sub> , V <sub>DD</sub> = 2.7 to 4.5 V	0.8 V <sub>DD</sub>			V
	V <sub>OH2</sub>	I <sub>OUT</sub> = -1 mA, FR, V <sub>DD</sub> = 2.7 to 4.5 V	0.8 V <sub>DD</sub>			V
	V <sub>OH3</sub>	I <sub>OUT</sub> = -80 μA, OSC <sub>2</sub> , V <sub>DD</sub> = 2.7 to 4.5 V	0.8 V <sub>DD</sub>			V
Low-level output voltage	V <sub>OL1</sub>	I <sub>OUT</sub> = 1.5 mA, DB <sub>0</sub> to DB <sub>7</sub> , V <sub>DD</sub> = 2.7 to 4.5 V			0.2 V <sub>DD</sub>	V
	V <sub>OL2</sub>	I <sub>OUT</sub> = 1 mA, FR, V <sub>DD</sub> = 2.7 to 4.5 V			0.2 V <sub>DD</sub>	V
	V <sub>OL3</sub>	I <sub>OUT</sub> = 80 μA, OSC <sub>2</sub> , V <sub>DD</sub> = 2.7 to 4.5 V			0.2 V <sub>DD</sub>	V
High-level leak current	I <sub>LOH</sub>	DB <sub>0</sub> to DB <sub>7</sub> , V <sub>IN/OUT</sub> = V <sub>DD</sub>			3	μA
Low-level leak current	I <sub>LOL</sub>	DB <sub>0</sub> to DB <sub>7</sub> , V <sub>IN/OUT</sub> = V <sub>SS</sub>			-3	μA
★ Driver output ON resistor	R <sub>ON1</sub>	T <sub>A</sub> = 25°C, V <sub>DD</sub> = 5 V, V <sub>LC5</sub> = V <sub>SS</sub>			7.5	kΩ
	R <sub>ON2</sub>	T <sub>A</sub> = 25°C, V <sub>DD</sub> = 3.5 V, V <sub>LC5</sub> = V <sub>SS</sub>			50	kΩ
Static current consumption	I <sub>DD0</sub>				1.0	μA
Dynamic current consumption	I <sub>DD1</sub>	External clock: 18 kHz			15.0	μA
		Self-oscillation: R = 1.3 MΩ			30.0	μA
★	I <sub>DD2</sub>	During access: t <sub>CYC</sub> = 200 kHz			500	μA
Input capacitance	C <sub>IN</sub>	T <sub>A</sub> = 25°C, f = 1 MHz			8.0	pF
★ Oscillator frequency	f <sub>OSC1</sub>	In self-oscillation, V <sub>DD</sub> = 5.0 V, R = 1.3 MΩ ± 2%	15	18	21	kHz
	f <sub>OSC2</sub>	In self-oscillation, V <sub>DD</sub> = 3.0 V, R = 1.3 MΩ ± 2%	11	16	21	kHz
★ Reset time	t <sub>r</sub>	/RESET↓ → Internal reset release	1.0		1000	μs

**Remark** The TYP. value is a reference value when T<sub>A</sub> = 25°C.

AC Characteristics 1 (Unless otherwise specified, T<sub>A</sub> = -40 to +85°C, V<sub>DD</sub> = 4.5 to 5.5 V)

**80 Series CPU Read/Write Timing**

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Address hold time	t <sub>AH8</sub>	A0	10			ns
Address setup time	t <sub>AW8</sub>		20			ns
System cycle time	t <sub>CYC8</sub>	/WR, /RD	1000			ns
Control pulse width	t <sub>CC</sub>		200			ns
Data setup time	t <sub>DS8</sub>	DB <sub>0</sub> to DB <sub>7</sub>	80			ns
Data hold time	t <sub>DH8</sub>		10			ns
/RD access time	t <sub>ACC8</sub>	DB <sub>0</sub> to DB <sub>7</sub> , C <sub>L</sub> = 100 pF			90	ns
Output disable time	t <sub>OH8</sub>		10		60	ns

**68 Series CPU Read/Write Timing**

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
System cycle time	t <sub>CYC6</sub>	A0, R,/W	1000			ns
Address setup time	t <sub>AW6</sub>		20			ns
Address hold time	t <sub>AH6</sub>		10			ns
Data setup time	t <sub>DS6</sub>	DB <sub>0</sub> to DB <sub>7</sub>	80			ns
Data hold time	t <sub>DH6</sub>		10			ns
Output disable time	t <sub>OH6</sub>	DB <sub>0</sub> to DB <sub>7</sub> , C <sub>L</sub> = 100 pF	10		60	ns
Access time	t <sub>ACC6</sub>				90	ns
Enable pulse width	Read	t <sub>EW</sub>	E	100		ns
	Write			80		ns

AC Characteristics 2 (Unless otherwise specified, T<sub>A</sub> = -40 to +85°C, V<sub>DD</sub> = 2.7 to 4.5 V)

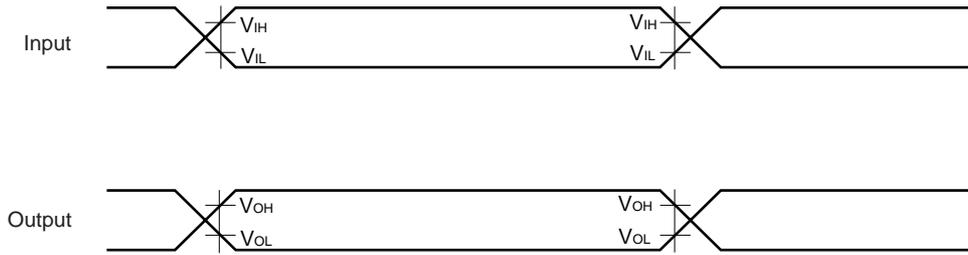
**80 Series CPU Read/Write Timing**

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Address hold time	t <sub>AH8</sub>	A0	20			ns
Address setup time	t <sub>AW8</sub>		40			ns
System cycle time	t <sub>CYC8</sub>	/WR, /RD	2000			ns
Control pulse width	t <sub>CC</sub>		400			ns
Data setup time	t <sub>DS8</sub>	DB <sub>0</sub> to DB <sub>7</sub>	160			ns
Data hold time	t <sub>DH8</sub>		20			ns
/RD access time	t <sub>ACC8</sub>	DB <sub>0</sub> to DB <sub>7</sub> , C <sub>L</sub> = 100 pF			180	ns
Output disable time	t <sub>OH8</sub>		20		120	ns

**68 Series CPU Read/Write Timing**

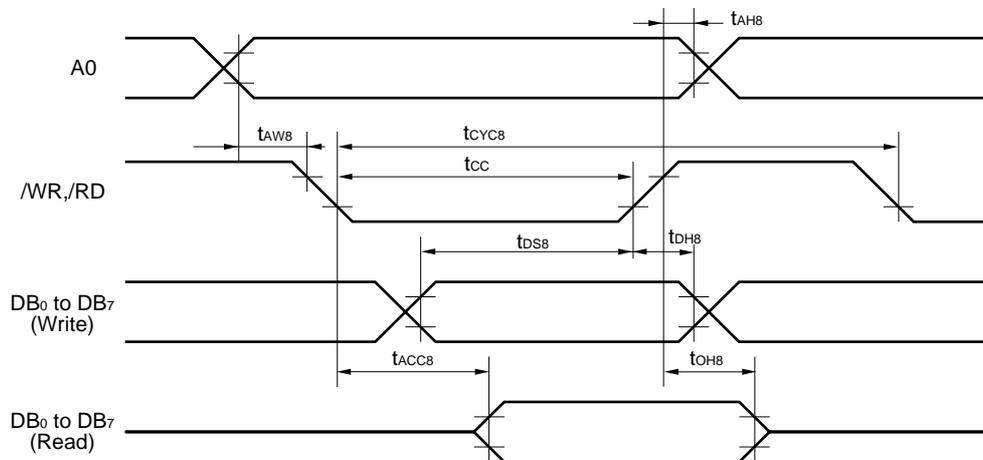
Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
System cycle time	t <sub>CYC6</sub>	A0, R,/W	2000			ns
Address setup time	t <sub>AW6</sub>		40			ns
Address hold time	t <sub>AH6</sub>		20			ns
Data setup time	t <sub>DS6</sub>	DB <sub>0</sub> to DB <sub>7</sub>	160			ns
Data hold time	t <sub>DH6</sub>		20			ns
Output disable time	t <sub>OH6</sub>	DB <sub>0</sub> to DB <sub>7</sub> , C <sub>L</sub> = 100 pF	20		120	ns
Access time	t <sub>ACC6</sub>				180	ns
Enable pulse width	Read	t <sub>EW</sub>	E	200		ns
	Write			160		ns

**Test Point of Switching Characteristics**

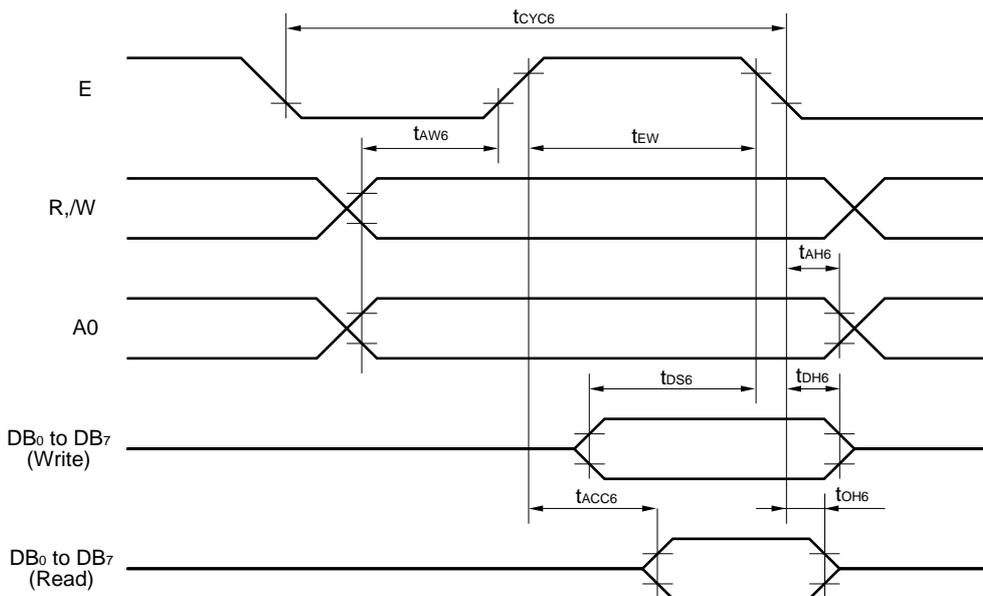


**Waveforms of Switching Characteristics**

**80 Series CPU Read/Write Timing**

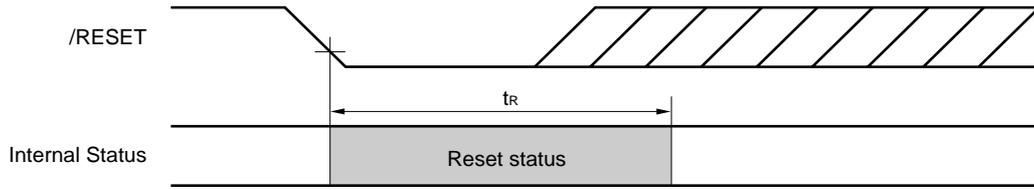


**68 Series CPU Read/Write Timing**

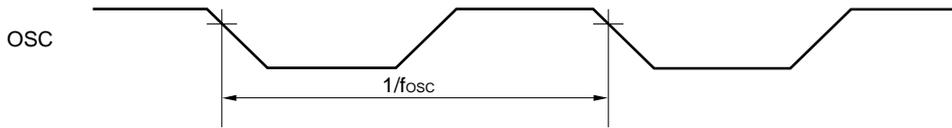


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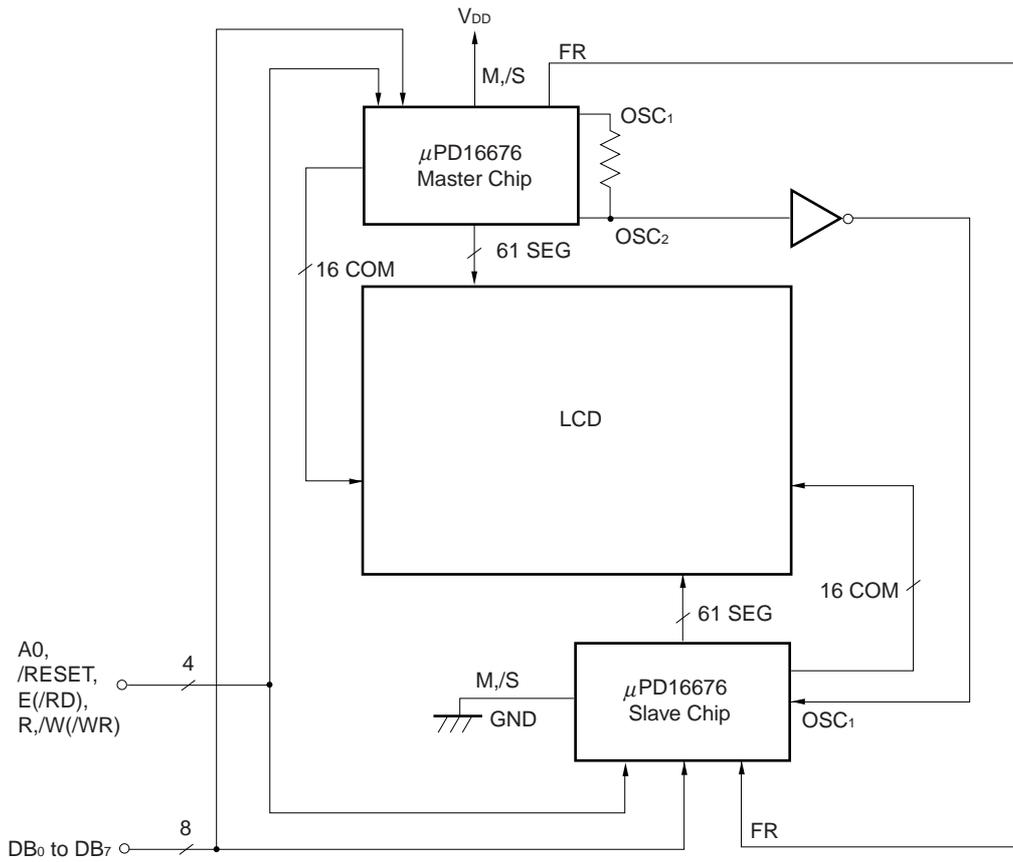
Reset



OSC



8. EXAMPLE of APPLICATION CIRCUIT



[MEMO]

[MEMO]

## NOTES FOR CMOS DEVICES

**① PRECAUTION AGAINST ESD FOR SEMICONDUCTORS**

Note:

Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

**② HANDLING OF UNUSED INPUT PINS FOR CMOS**

Note:

No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to  $V_{DD}$  or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

**③ STATUS BEFORE INITIALIZATION OF MOS DEVICES**

Note:

Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

## ★ Reference Documents

NEC Semiconductor Device Reliability/Quality Control System (C10983E)

Quality Grades to NEC's Semiconductor Devices (C11531E)

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